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	RULE			

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** CONTINUING DATA *****

This application is a CIP of 09/254,755 03/08/1999 ABN
 and is a CIP of 09/254,843 03/11/1999 PAT 6,359,680
 and is a CIP of 09/673,963 11/30/2000 PAT 6,495,848 *
 and is a CIP of 09/452,031 11/30/1999 PAT 6,431,870
 and is a CIP of 09/452,034 11/30/1999 ABN
 and is a CIP of 09/560,131 04/28/2000 PAT 6,744,914
 and is a CIP of 09/560,132 04/28/2000 PAT 6,771,809
 and is a CIP of 09/560,583 04/28/2000 PAT 6,738,508
 and is a CIP of 09/560,645 04/28/2000 PAT 6,728,423
 and is a CIP of 09/560,644 04/28/2000 PAT 6,413,084
 and is a CIP of 09/560,133 04/28/2000 PAT 6,744,932
 and is a CIP of 09/560,641 04/28/2000 PAT 6,512,994
 and is a CIP of 09/560,584 04/28/2000
 and is a CIP of 09/560,134 04/28/2000 PAT 6,851,949
 and is a CIP of 09/616,093 07/13/2000 PAT 6,532,299
 which is a CON of 09/254,755 03/08/1999 ABN
 (*)Data provided by applicant is not consistent with PTO records.

** FOREIGN APPLICATIONS *****

IF REQUIRED, FOREIGN FILING LICENSE GRANTED ** SMALL ENTITY **

** 05/01/2001

Foreign Priority claimed	<input type="checkbox"/> yes <input type="checkbox"/> no	STATE OR COUNTRY	SHEETS DRAWING	TOTAL CLAIMS	INDEPENDENT CLAIMS
35 USC 119 (a-d) conditions met	<input type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after Allowance	GERMANY	51	82	8
Verified and Acknowledged	Examiner's Signature	Initials			

ADDRESS

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TITLE

SCANNING SYSTEM AND CALIBRATION METHOD FOR CAPTURING PRECISE THREE-DIMENSIONAL
 INFORMATION OF OBJECTS